

Test Laboratory: Compliance Certification Services

1_HAC_E_Device PCS band (Backlight on - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1851.25 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

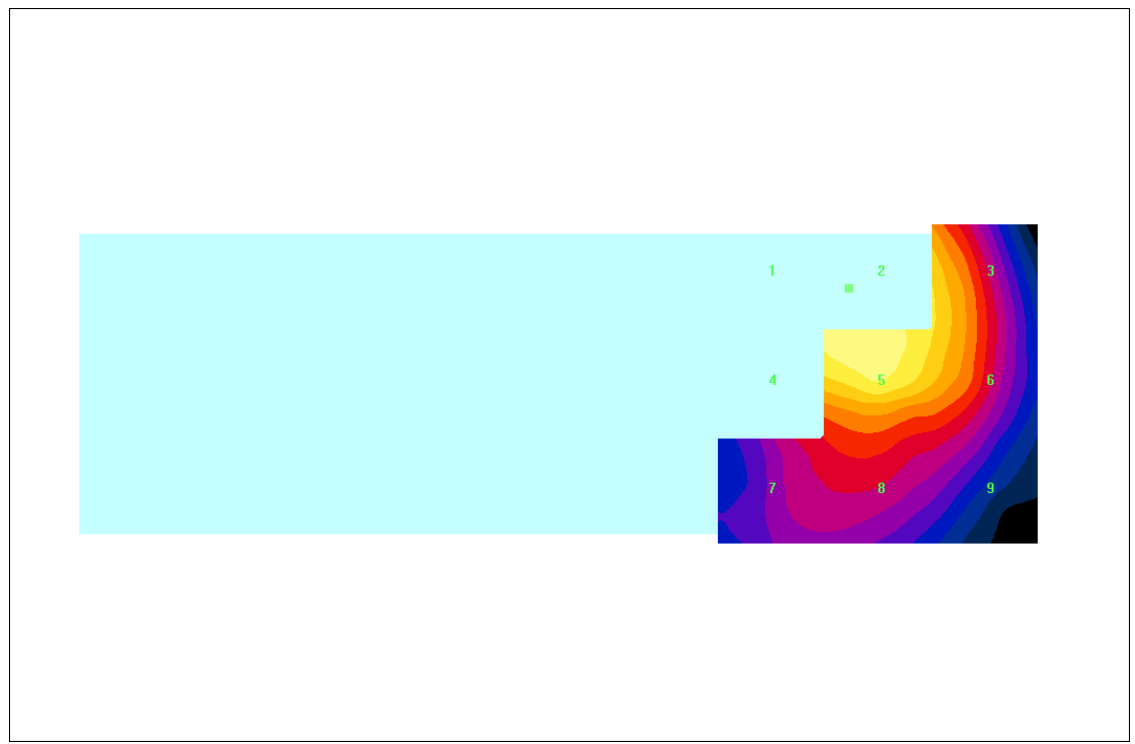
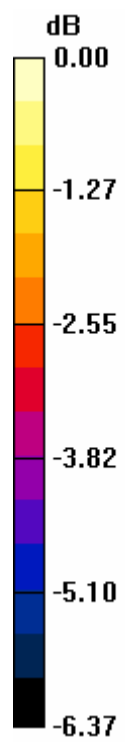
Maximum value of Total field (slot averaged) = 56.3 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 54.4	Grid 2 56.9	Grid 3 49.6	Grid 1 56.6	Grid 2 59.1	Grid 3 51.5
Grid 4 52.0	Grid 5 54.1	Grid 6 49.3	Grid 4 54.1	Grid 5 56.3	Grid 6 51.3
Grid 7 40.2	Grid 8 42.0	Grid 9 39.6	Grid 7 41.8	Grid 8 43.6	Grid 9 41.2

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 56.9V/m

Test Laboratory: Compliance Certification Services

1_HAC_E_Device PCS band (Backlight on - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1880 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

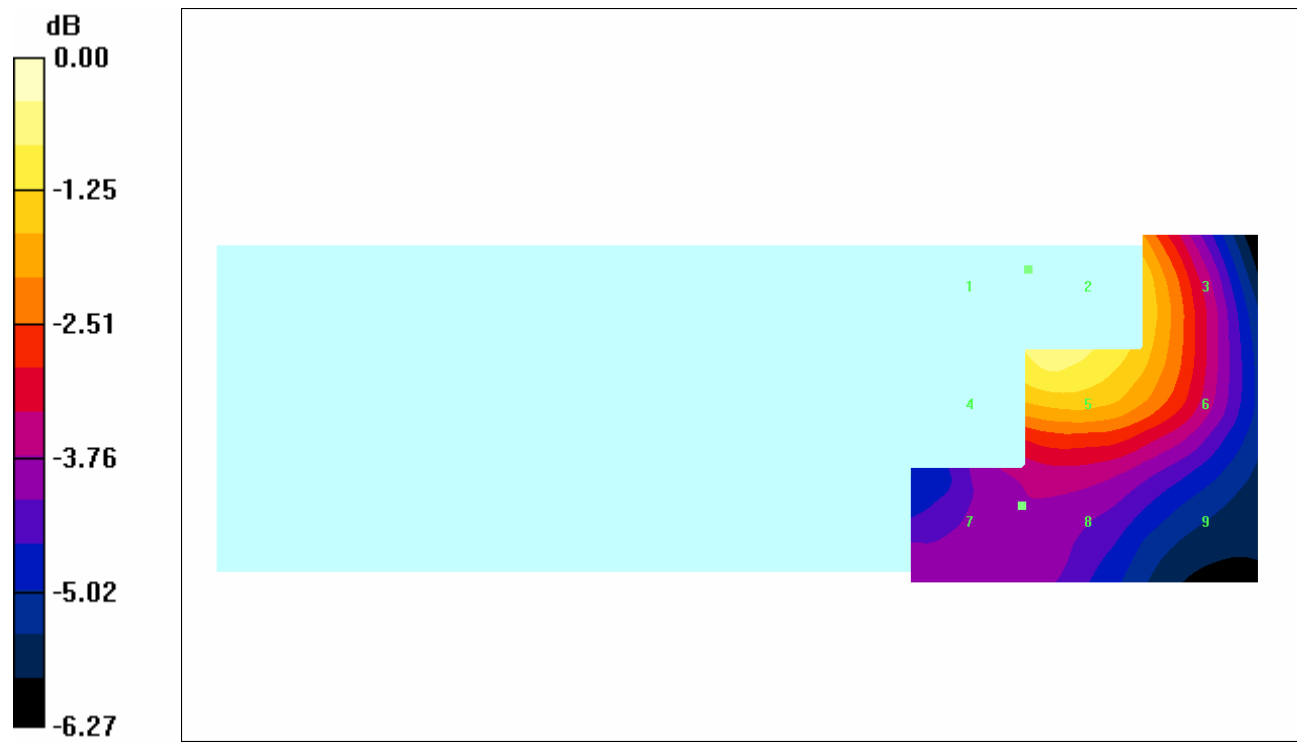
Maximum value of Total field (slot averaged) = 54.0 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 56.1	Grid 2 56.1	Grid 3 48.5	Grid 1 58.3	Grid 2 58.3	Grid 3 50.4
Grid 4 50.9	Grid 5 52.0	Grid 6 47.4	Grid 4 52.9	Grid 5 54.0	Grid 6 49.2
Grid 7 37.3	Grid 8 38.1	Grid 9 35.9	Grid 7 38.7	Grid 8 39.6	Grid 9 37.3

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 56.1V/m

Test Laboratory: Compliance Certification Services

1_HAC_E_Device PCS band (Backlight on - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1908.75 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

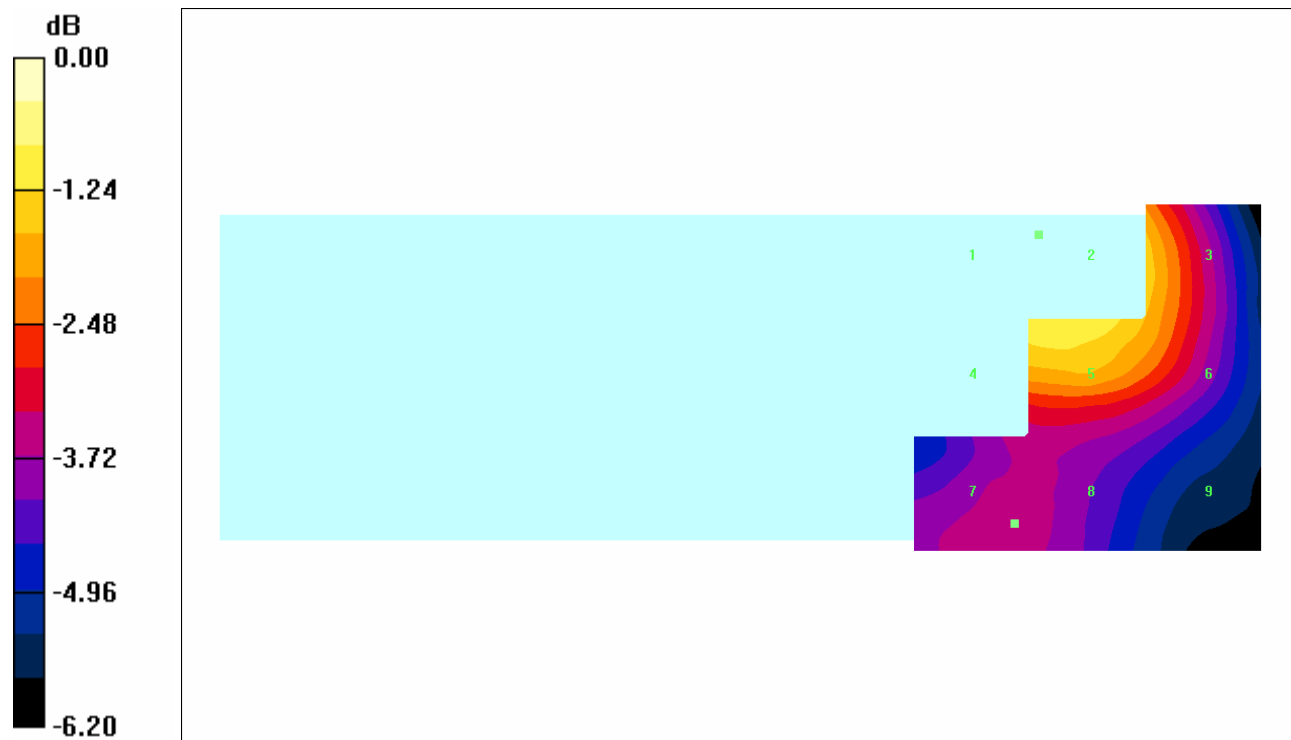
Maximum value of Total field (slot averaged) = 48.1 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 50.9	Grid 2 51.0	Grid 3 43.4	Grid 1 52.9	Grid 2 53.0	Grid 3 45.1
Grid 4 45.4	Grid 5 46.3	Grid 6 42.0	Grid 4 47.2	Grid 5 48.1	Grid 6 43.7
Grid 7 34.2	Grid 8 34.2	Grid 9 31.8	Grid 7 35.5	Grid 8 35.5	Grid 9 33.0

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 51.0V/m

Test Laboratory: Compliance Certification Services

2_HAC_E_Device PCS band (Backlight off - Keypad open)**DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01**

Communication System: CDMA PCS band; Frequency: 1851.25 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA;
- Measurement SW: DAS4, V4.5 Build 19;

E Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 54.9 V/m

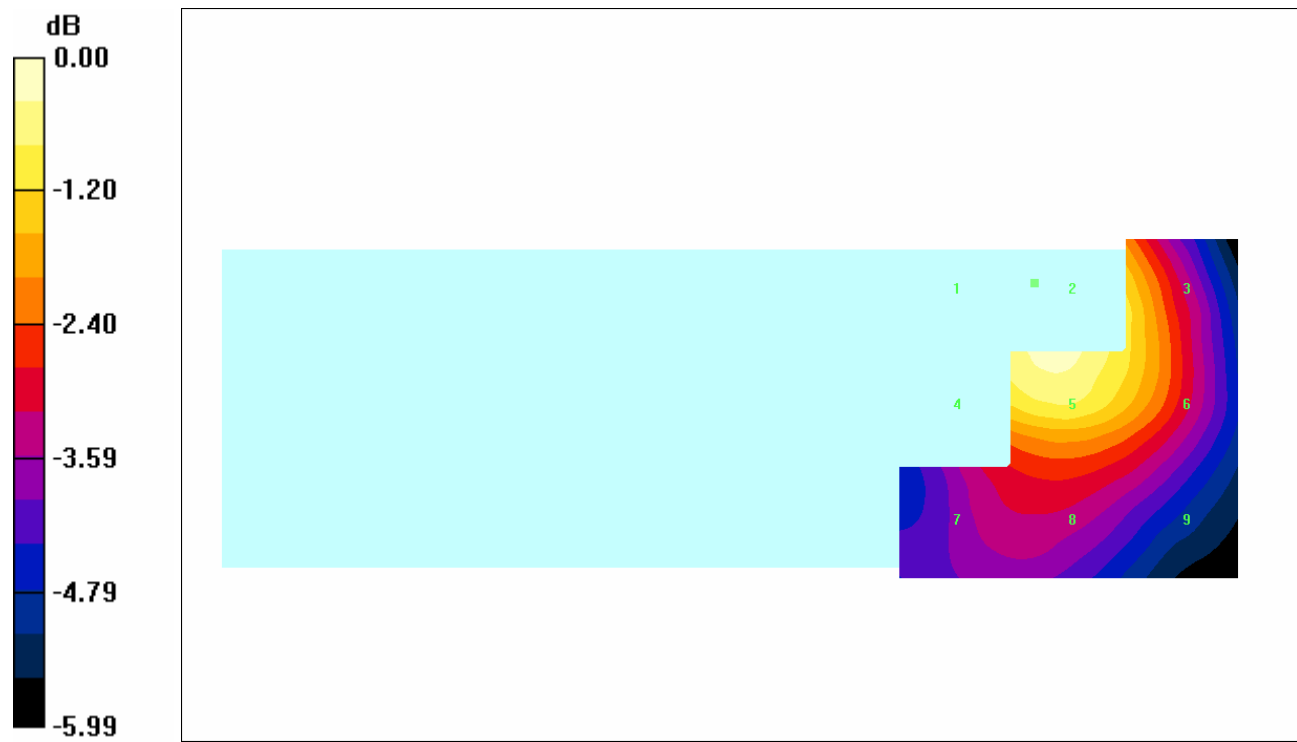
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3
53.3	54.3	48.1
Grid 4	Grid 5	Grid 6
50.5	52.8	47.9
Grid 7	Grid 8	Grid 9
39.3	40.5	38.5

Grid 1	Grid 2	Grid 3
55.4	56.4	50.0
Grid 4	Grid 5	Grid 6
52.4	54.9	49.8
Grid 7	Grid 8	Grid 9
40.8	42.1	40.0

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 54.3V/m

Test Laboratory: Compliance Certification Services

2_HAC_E_Device PCS band (Backlight off - Keypad open)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1880 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA;
- Measurement SW: DAS4, V4.5 Build 19;

E Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 53.9 V/m

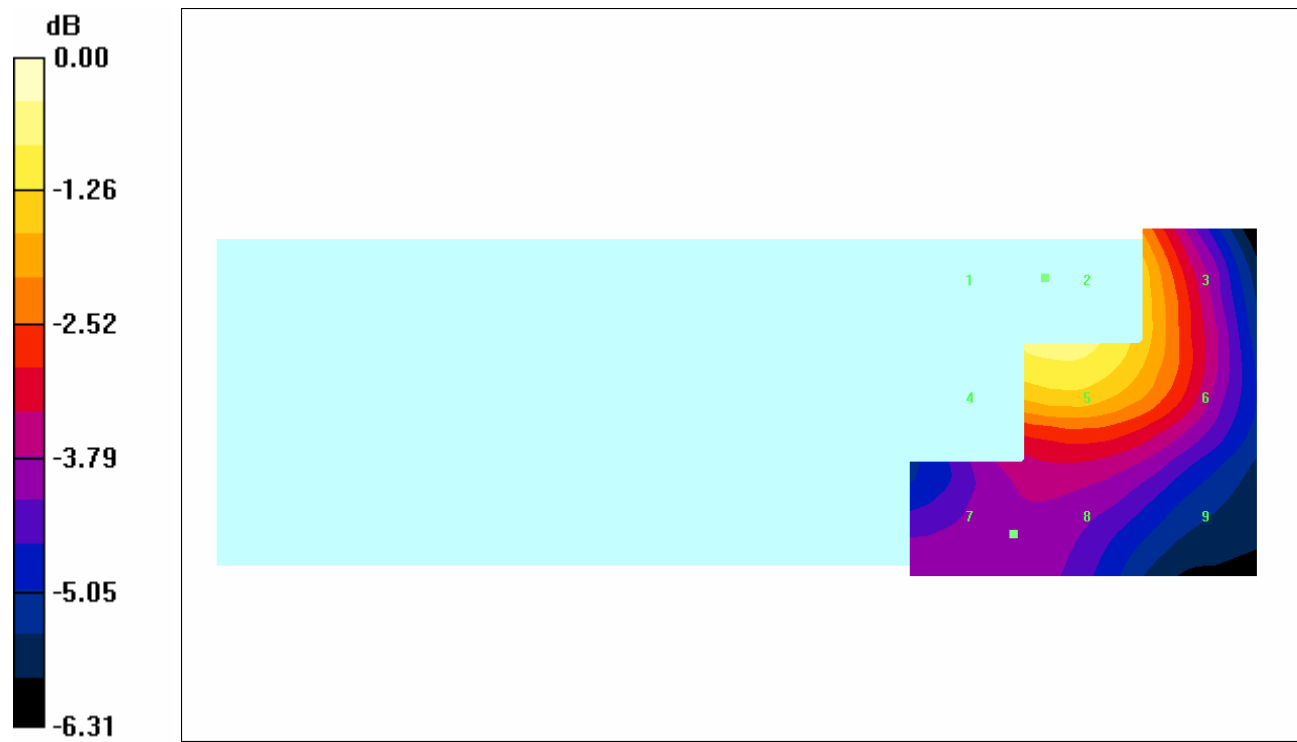
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3
55.4	55.9	47.6
Grid 4	Grid 5	Grid 6
50.8	51.9	47.1
Grid 7	Grid 8	Grid 9
37.4	38.1	36.2

Grid 1	Grid 2	Grid 3
57.5	58.1	49.5
Grid 4	Grid 5	Grid 6
52.8	53.9	49.0
Grid 7	Grid 8	Grid 9
38.9	39.6	37.6

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 55.9V/m

Test Laboratory: Compliance Certification Services

2_HAC_E_Device PCS band (Backlight off - Keypad open)**DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01**

Communication System: CDMA PCS band; Frequency: 1908.75 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA;
- Measurement SW: DAS4, V4.5 Build 19;

E Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 48.4 V/m

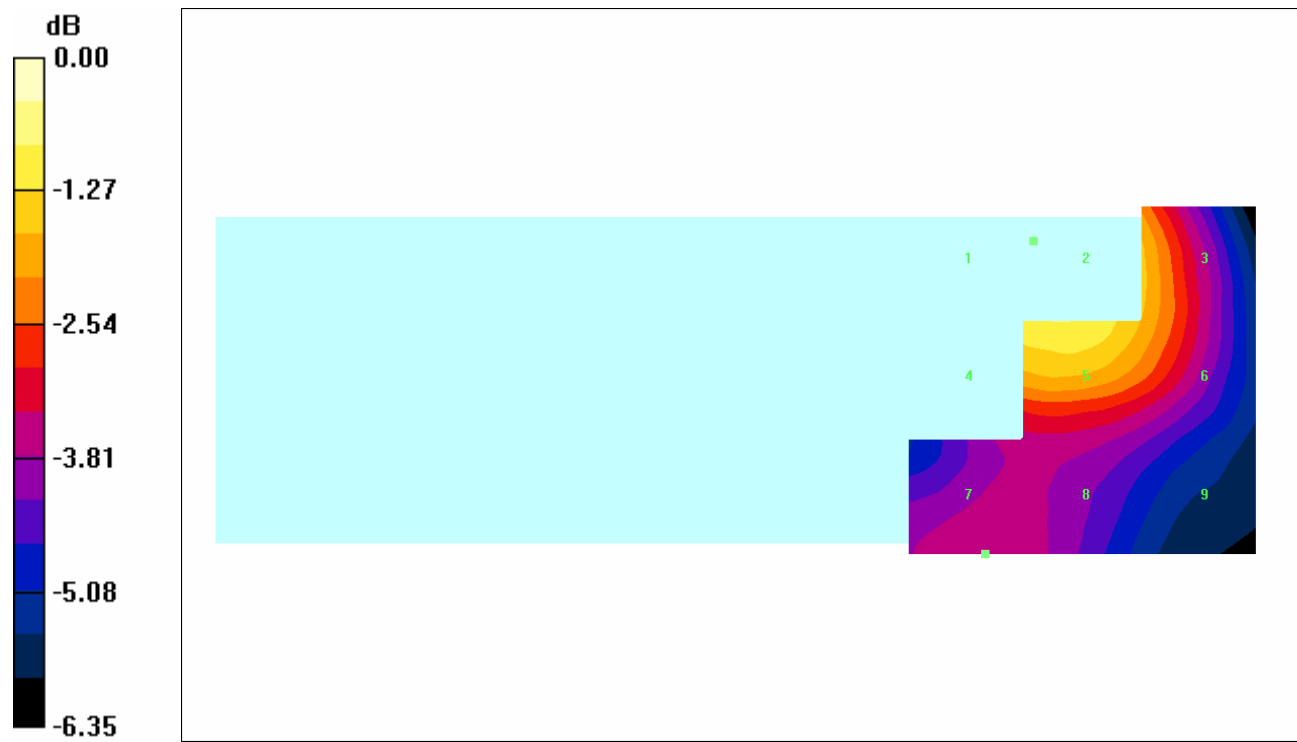
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3
51.1	51.3	43.0
Grid 4	Grid 5	Grid 6
45.8	46.6	42.1
Grid 7	Grid 8	Grid 9
34.3	34.3	32.0

Grid 1	Grid 2	Grid 3
53.1	53.3	44.6
Grid 4	Grid 5	Grid 6
47.6	48.4	43.8
Grid 7	Grid 8	Grid 9
35.6	35.7	33.2

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 51.3V/m

Test Laboratory: Compliance Certification Services

1_HAC_E_Device PCS band (Backlight on - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1851.25 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

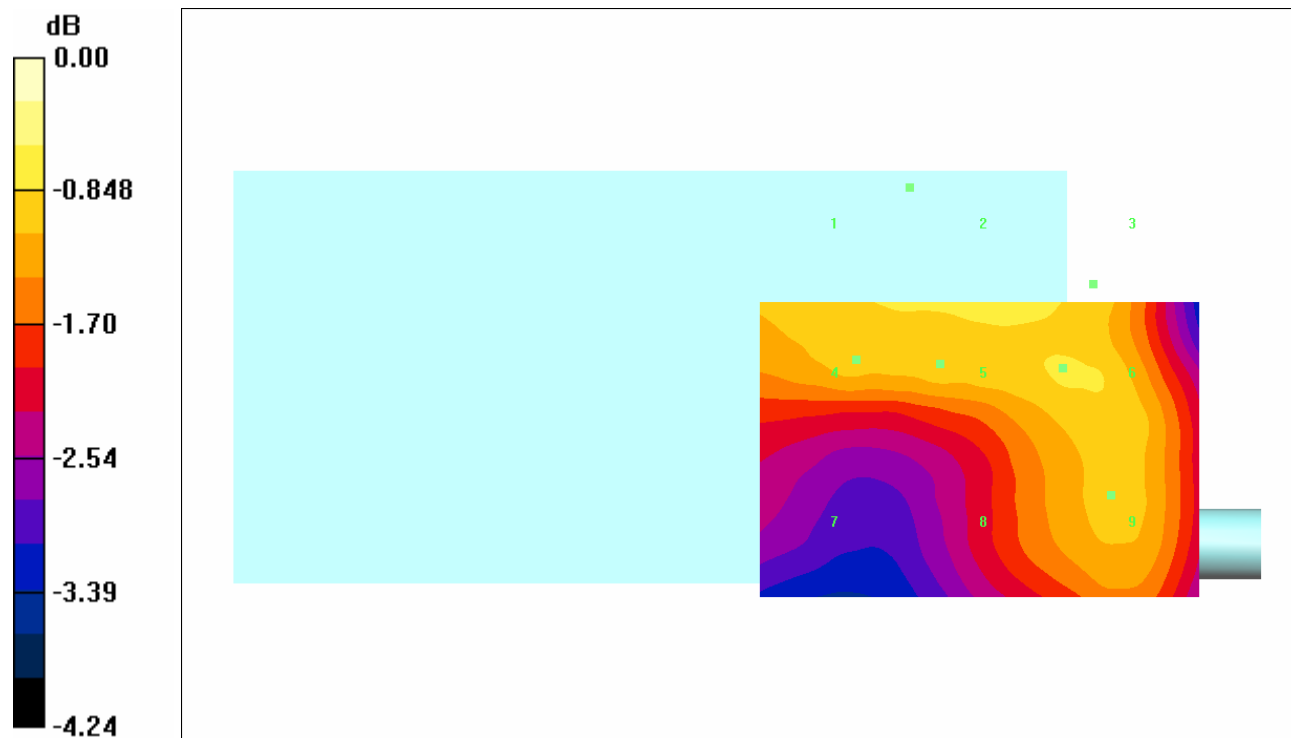
Maximum value of Total field (slot averaged) = 56.6 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 59.2	Grid 2 59.2	Grid 3 55.3	Grid 1 61.5	Grid 2 61.5	Grid 3 57.5
Grid 4 54.0	Grid 5 54.5	Grid 6 54.0	Grid 4 56.1	Grid 5 56.6	Grid 6 56.1
Grid 7 46.0	Grid 8 50.9	Grid 9 52.9	Grid 7 47.8	Grid 8 52.9	Grid 9 55.0

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 59.2V/m

Test Laboratory: Compliance Certification Services

1_HAC_E_Device PCS band (Backlight on - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1880 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

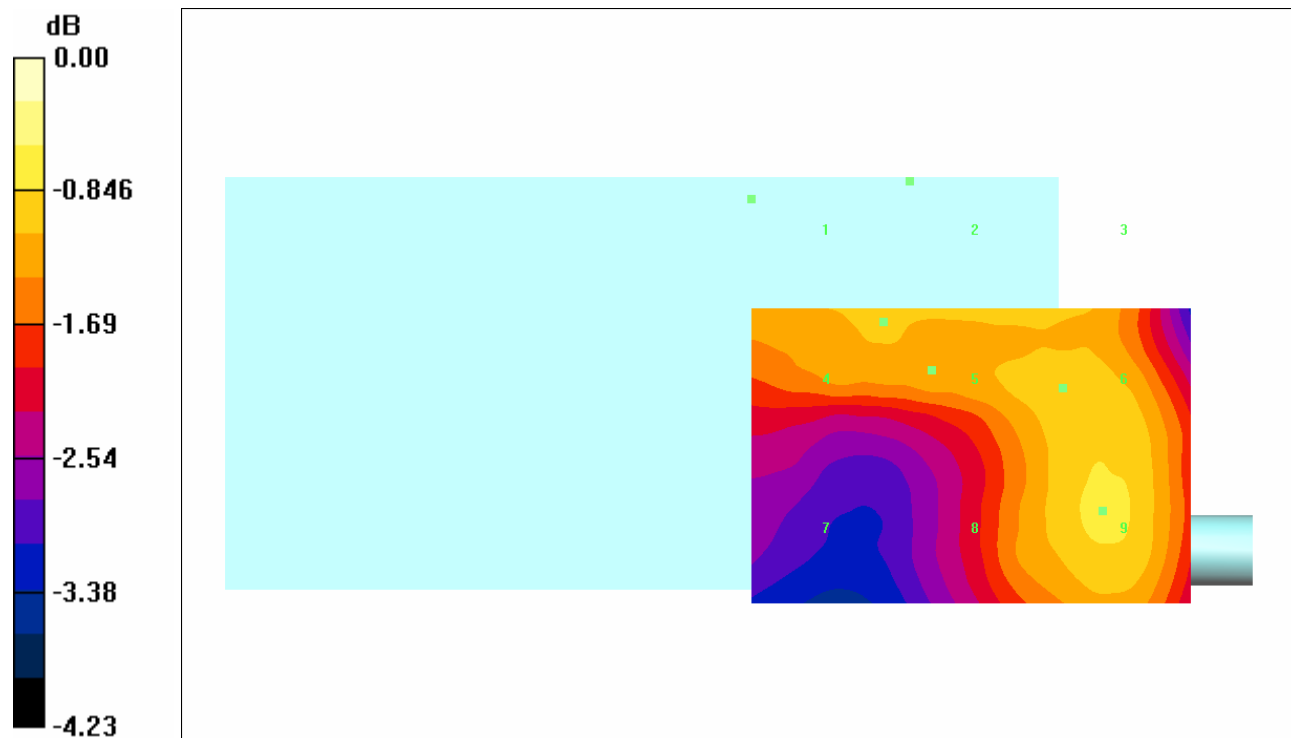
Maximum value of Total field (slot averaged) = 58.3 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 61.0	Grid 2 61.1	Grid 3 56.0	Grid 1 63.4	Grid 2 63.5	Grid 3 58.2
Grid 4 54.3	Grid 5 54.7	Grid 6 55.4	Grid 4 56.4	Grid 5 56.9	Grid 6 57.6
Grid 7 46.2	Grid 8 53.5	Grid 9 56.1	Grid 7 48.0	Grid 8 55.5	Grid 9 58.3

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 61.1V/m

Test Laboratory: Compliance Certification Services

1_HAC_E_Device PCS band (Backlight on - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1908.75 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

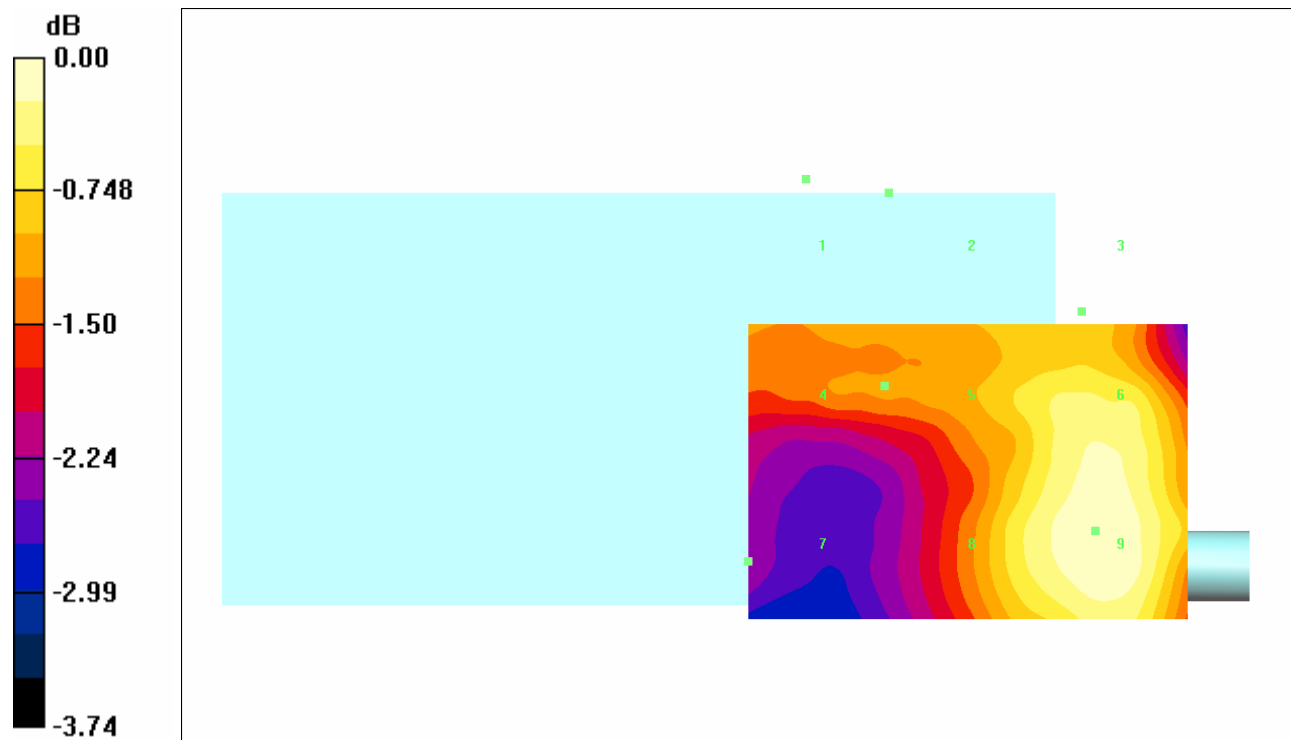
Maximum value of Total field (slot averaged) = 56.9 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 54.8	Grid 2 54.8	Grid 3 51.0	Grid 1 56.9	Grid 2 56.9	Grid 3 53.0
Grid 4 48.1	Grid 5 51.2	Grid 6 53.7	Grid 4 50.0	Grid 5 53.2	Grid 6 55.8
Grid 7 42.7	Grid 8 52.6	Grid 9 54.8	Grid 7 44.3	Grid 8 54.7	Grid 9 56.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services

2_HAC_E_Device PCS band (Backlight off - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1851.25 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

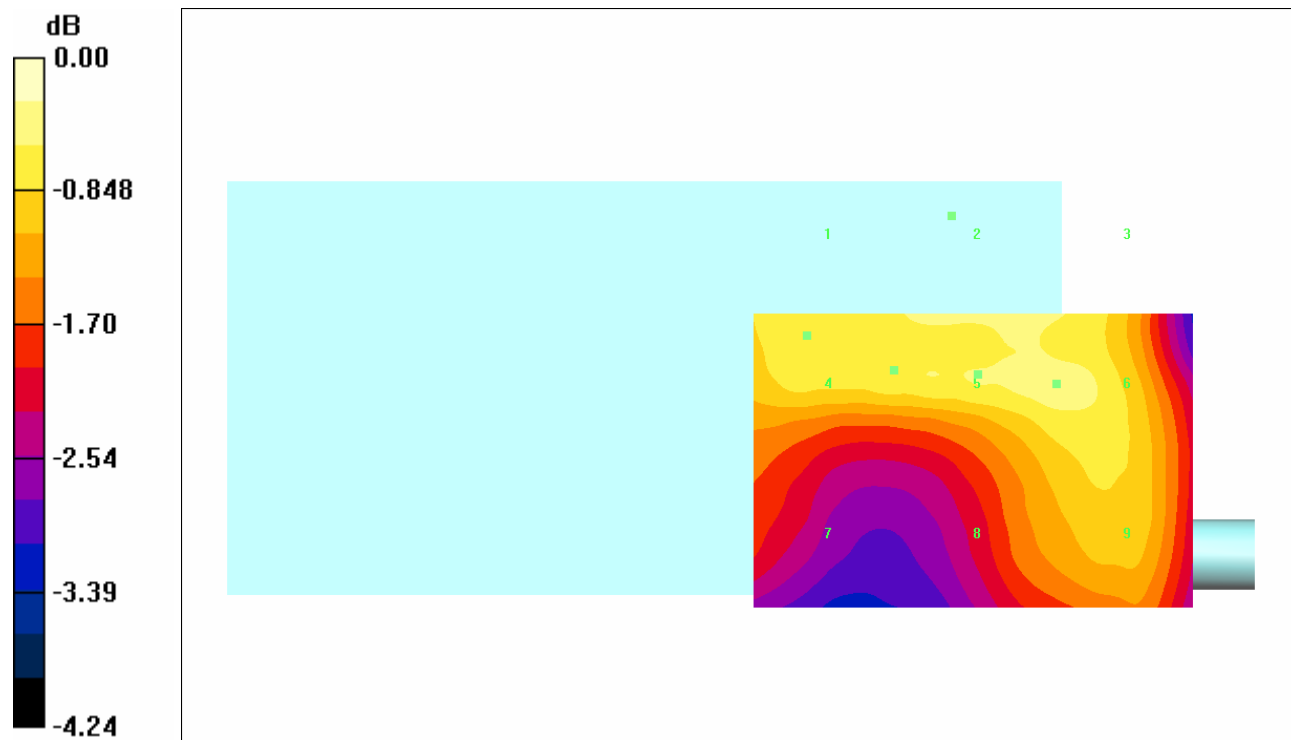
Maximum value of Total field (slot averaged) = 55.4 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 55.5	Grid 2 55.6	Grid 3 52.9	Grid 1 57.7	Grid 2 57.8	Grid 3 55.0
Grid 4 51.9	Grid 5 53.0	Grid 6 53.3	Grid 4 54.0	Grid 5 55.1	Grid 6 55.4
Grid 7 46.3	Grid 8 49.1	Grid 9 50.8	Grid 7 48.1	Grid 8 51.0	Grid 9 52.8

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 55.6V/m

Test Laboratory: Compliance Certification Services

2_HAC_E_Device PCS band (Backlight off - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1880 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

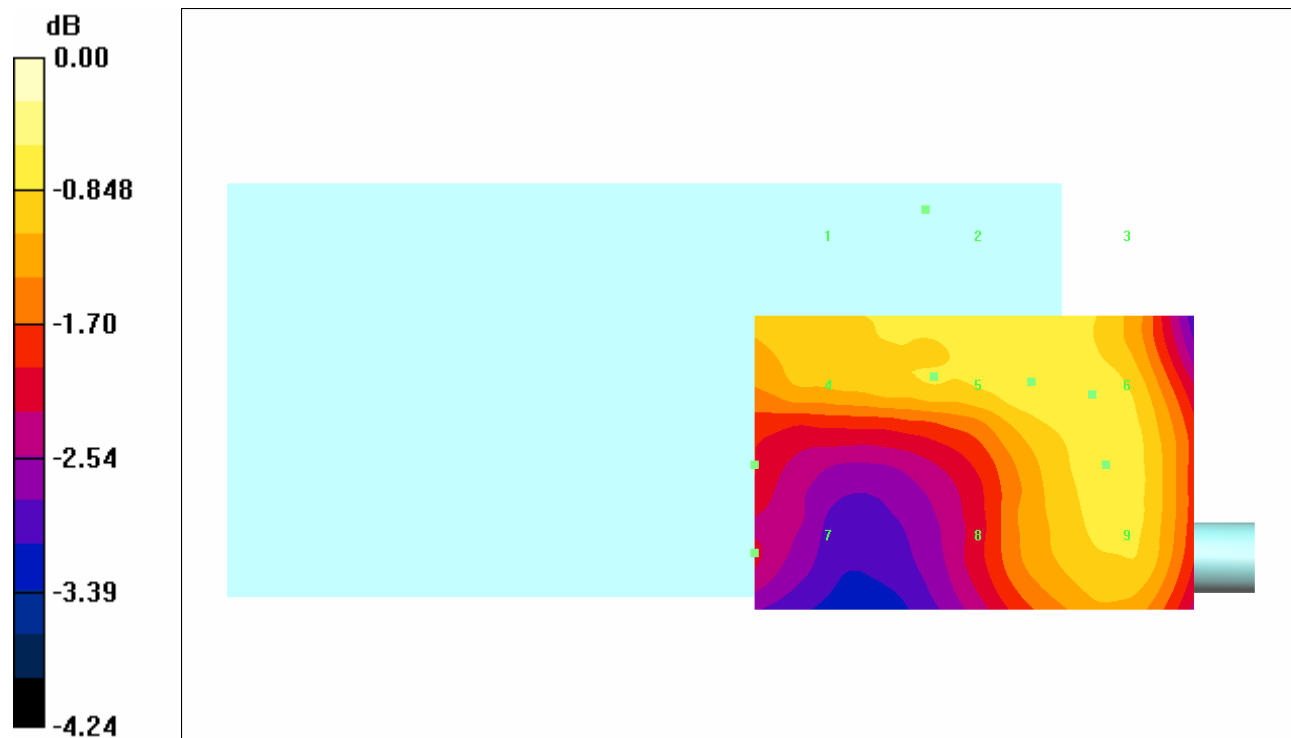
Maximum value of Total field (slot averaged) = 57.0 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 58.1	Grid 2 58.5	Grid 3 55.3	Grid 1 60.4	Grid 2 60.8	Grid 3 57.5
Grid 4 53.4	Grid 5 54.6	Grid 6 54.9	Grid 4 55.5	Grid 5 56.7	Grid 6 57.0
Grid 7 46.7	Grid 8 51.7	Grid 9 54.0	Grid 7 48.6	Grid 8 53.8	Grid 9 56.1

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 58.5V/m

Test Laboratory: Compliance Certification Services

2_HAC_E_Device PCS band (Backlight off - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA PCS band; Frequency: 1908.75 MHz; Duty Cycle: 1:1.08

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

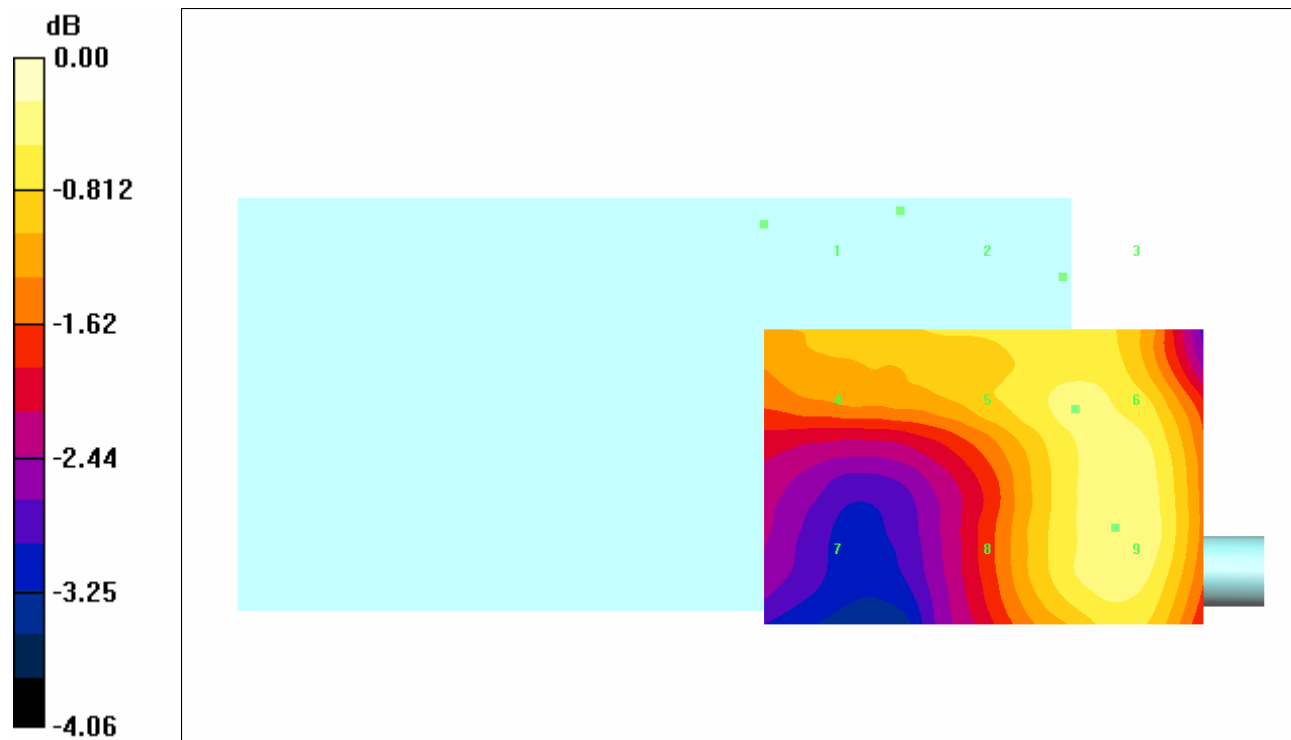
Maximum value of Total field (slot averaged) = 55.2 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 55.0	Grid 2 54.9	Grid 3 51.7	Grid 1 57.1	Grid 2 57.1	Grid 3 53.7
Grid 4 49.7	Grid 5 51.9	Grid 6 52.7	Grid 4 51.7	Grid 5 53.9	Grid 6 54.7
Grid 7 42.5	Grid 8 50.5	Grid 9 53.1	Grid 7 44.2	Grid 8 52.5	Grid 9 55.2

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 55.0V/m